



# Risk analysis on IC in Schneider Electric

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Life Is On



A photograph of two men in a factory setting. The man on the left is wearing a white shirt and a yellow safety vest. The man on the right is wearing a dark suit and glasses. They are both looking down at a tablet computer held by the man in the suit. The background shows industrial equipment and a factory floor.

# Summary

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1. Schneider Electric / EME laboratory
2. Mission Profile: Customer expectation
3. Risk analysis on IC
4. Difficulties / Concerns

# Schneider Electric, the global specialist in energy management and automation

€25 billion

FY 2014 revenues

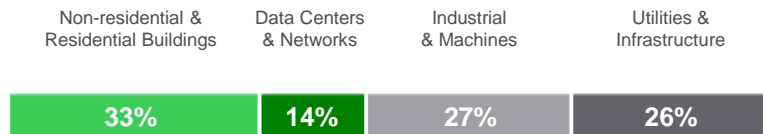
~5%

of revenues devoted to R&D

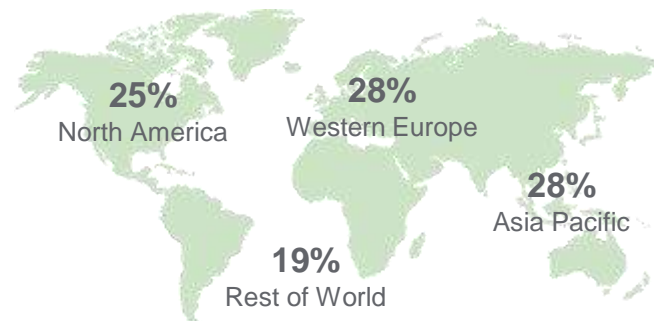
~170,000

people in 100+ countries

## Diversified end markets – FY 2014 revenues<sup>1</sup>



## Balanced geographies – FY 2014 revenues<sup>1</sup>





Energy is the base of life.

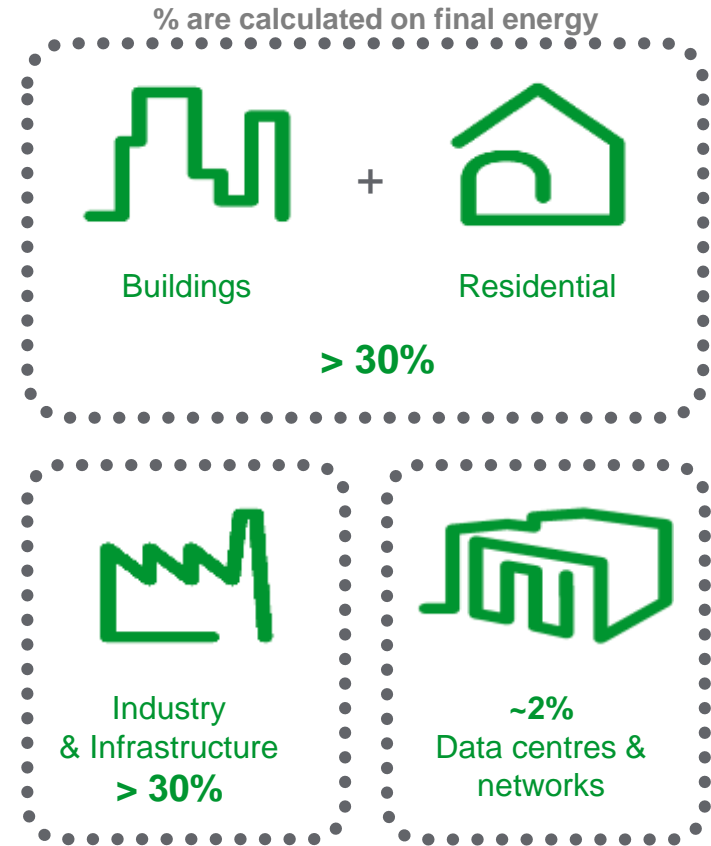
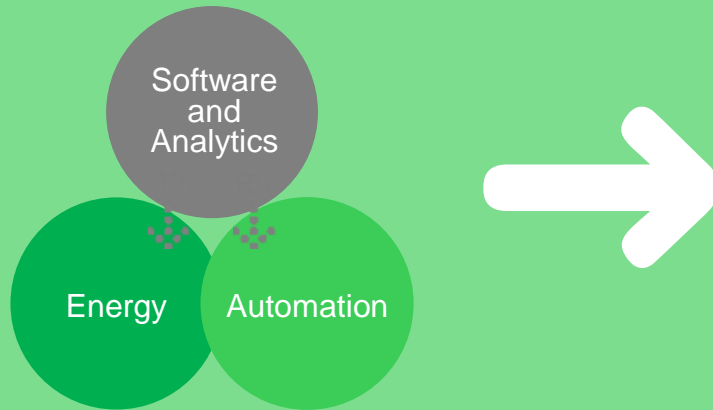
# Life Is On

when energy is on.....

We ensure energy is on by making it

- Safe
- Reliable
- Efficient
- Connected
- Sustainable

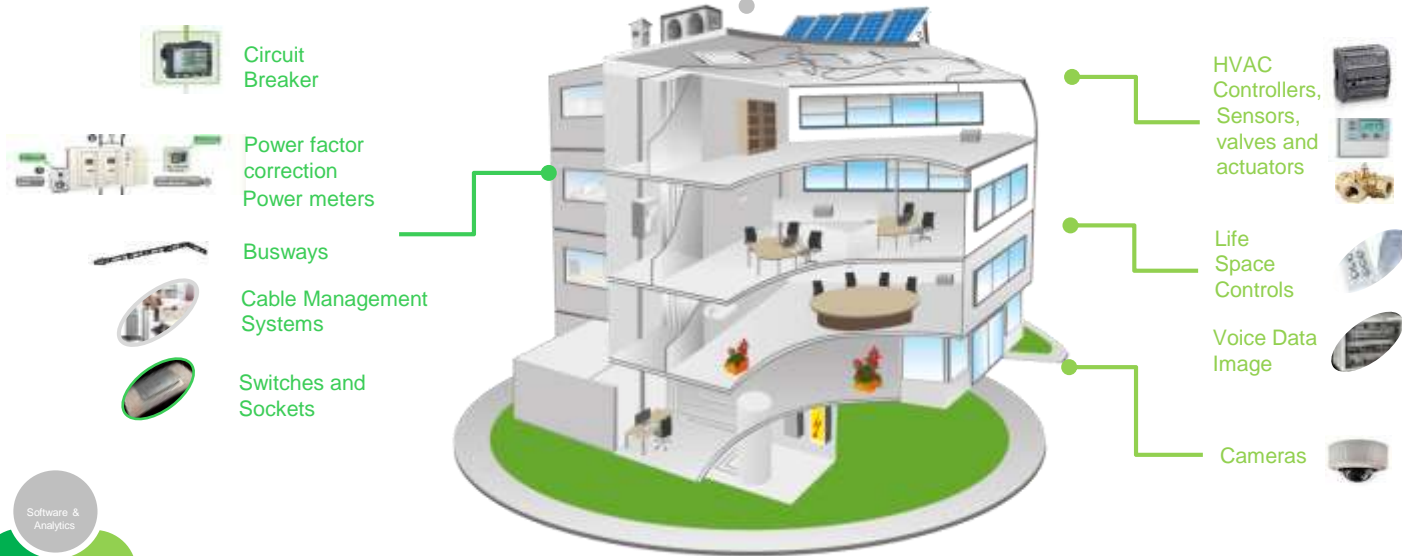
At Schneider Electric , we combine  
**Energy Management, Automation**  
and **Software** serving 4 markets, i.e.  
70% of the world energy consumption



# Life is On with Schneider Electric Building Solutions:

From grid to floor space, we ensure safety, comfort, reliability, efficiency and sustainability

Security Management    Building Management    Power Management



Key Buildings  
Sub-Segments



Hotel



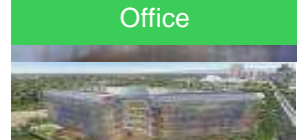
Hospital



Retail



Office



Life Science



# Life is On with Schneider Datacenter Solutions:

From rack to cyber space, we optimize performance, speed and cost



HV/MV &  
MV/LV  
Transformers



MV and LV  
Switchboards  
& Switchgears



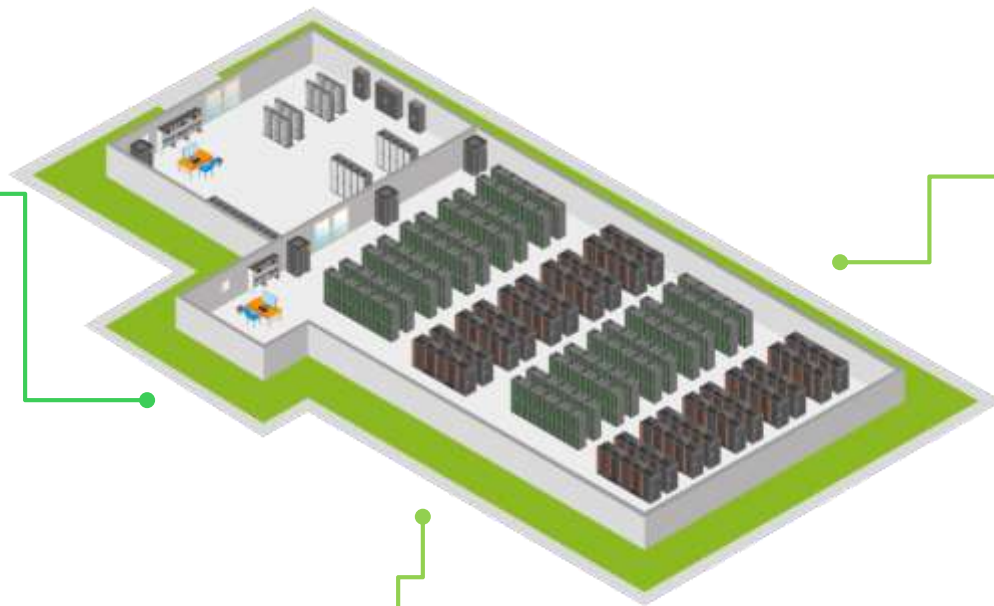
Modular UPS



Sensors &  
Meters



Busway



Network connectivity  
& Cable management



Floors,  
Rack  
systems



Flexible Air  
Containment



Room/Row/Rack  
precision cooling



Indirect Free  
Cooling



Chillers

Cooling  
VSD & Control



Row Modular  
UPS & PDU



Lighting  
Control

Access Control,  
CCTV





# Life is On with Schneider Electric Smart City Solutions:

From **downtown** to **suburb**, we deliver **urban efficiency** today



## Smart Water

- Plant & Network Energy Performance
- Water Distribution Optimization & Loss Mgt
- Stormwater management and Urban Flooding
- Irrigation Management



## Smart Energy

- Smart Grid Asset Management, Smart Generation, Demand Side Management, Utility Services
- Renewables Integration & Micro Grid
- District Heating/Cooling Management
- Gas Distribution Management
- Shore Connection

## Smart Buildings & Homes



- Multiple Disparate Buildings Management
- High Performance Buildings
- Flexible Buildings
- Efficient Homes

## Smart Public Services



- Public Safety: Video Surveillance
- Smart Street Lighting Management



## Smart Mobility

- EV Charging Infrastructure & Supervision Services
- Traffic Management
- Tunnel Management
- Tolling Management
- Railway Management
- Airport Solutions

## Smart Data Center



- Efficient Data Centers
- Prefabricated Data Centers
- Infrastructure Enabled Management Services



## Smart Integration

- City-wide Platforms
- Energy & Sustainability Resource Management
- Urban Efficiency Platform
- District Energy Management Information System
- Cross-domain Application
  - Weather
  - GIS
  - Asset Management
- City Strategy Services
  - Sustainability Services
  - Smart Cities Advisory Services
  - Energy Performance Contracting



Life Is On

**Schneider**  
Electric

Our capabilities allow us to deliver tangible results for customers, wherever they might be.



# Electronics and Materials Expertise Lab. (EME)

**Provide technological expertise support to all Schneider Electric Businesses for product quality mastery**

- Qualification
- Failure analysis
- Consulting

## **In the field of**

- Electronics
- Materials
- Metals
- Assembly



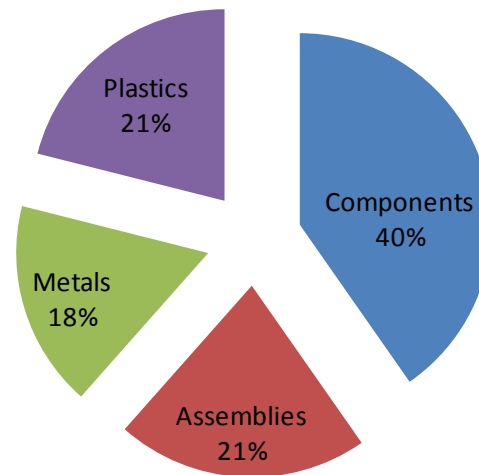
# EME lab in few figures

**19** experts

**550** m<sup>2</sup> lab

**5** M€ equipment

**+** a wide external laboratory network



**750** analyses performed / year  
(2014 figures)

**7500** expertise reports accessible in  
our iExpert database



## Mission Profile: Customer Expectation



Electronics to be safe, reliable, connected, green, in our customer environment during the expected lifetime.....



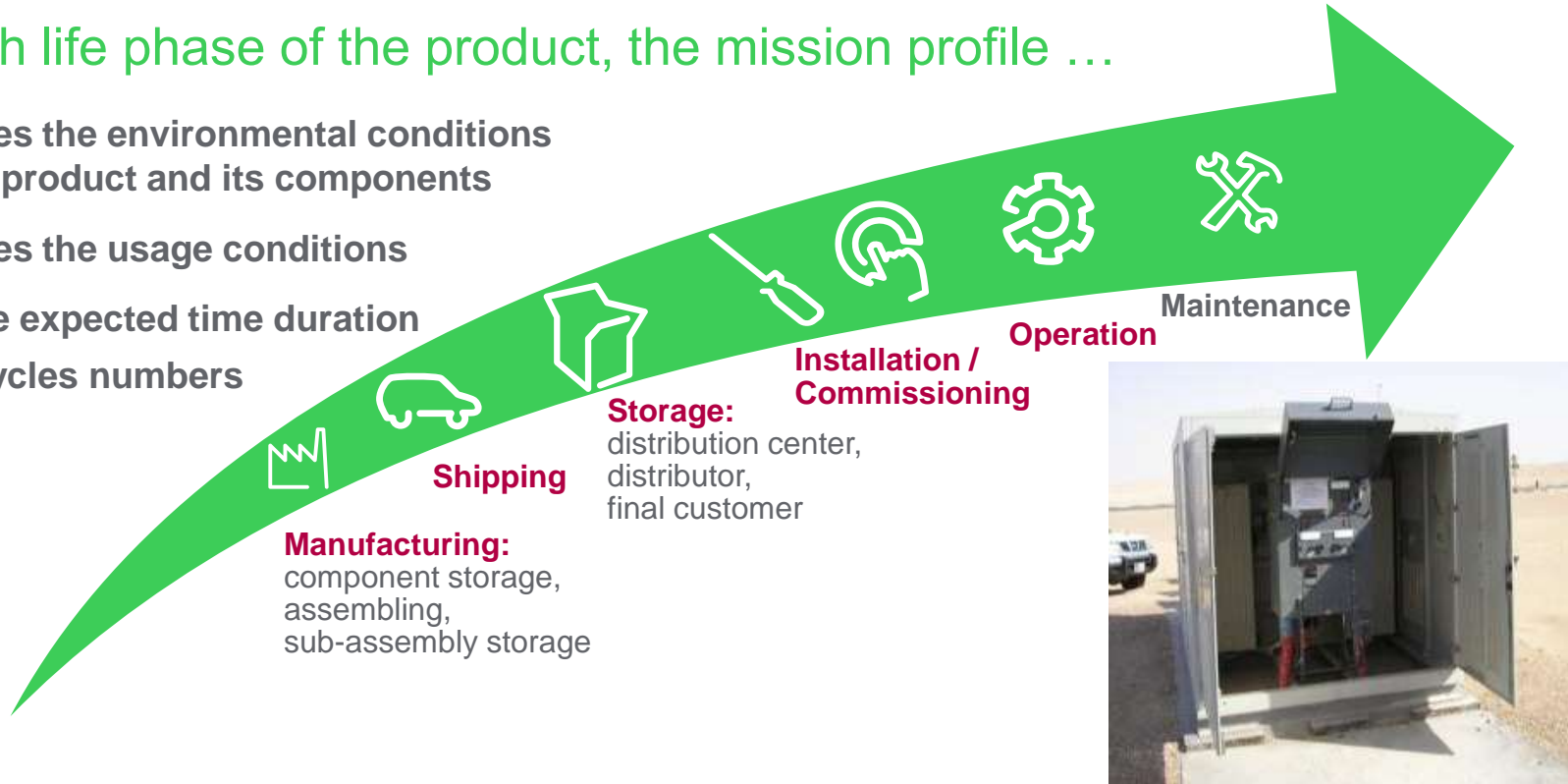
Varieties of environmental constraints in our final customers applications require high reliability & requirements levels where failures cannot be tolerated!



# Our Customers expect the “legendary reliability of Schneider Electric products “!

For each life phase of the product, the mission profile ...

1. describes the environmental conditions of the product and its components
2. describes the usage conditions
3. fixes the expected time duration and cycles numbers



# Product Mission Profile Example

## Storage

Temperature (close to the component)	Humidity (close to the component)	Duration
30°C	80%RH	6 months

## Operation

Temperature (close to the component)	Humidity (close to the component)	Duration
90°C	7%	61320 h
105°C	5%	26280h

Temperature (close to the component)	Humidity (close to the component)	Duration
50°C	15%	157680h
60°C	10%	8760h



10 years

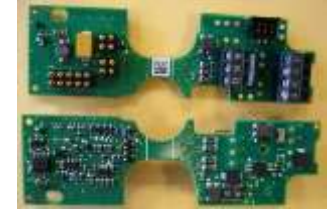
20 years

**Standard components market gets lower level requirements than Schneider industrial products**

A woman with blonde hair tied back, wearing a dark jacket and a red and blue patterned scarf, is smiling and looking down at a white smartphone in her hands. She is also holding a pair of glasses. The background is a blurred outdoor scene with other people.

## Risk analysis on IC

# Risk analysis



Quality and Reliability data from the component manufacturer are compared to the need of the project (mission profile), in order to identify the risks related to the technology and its use in the final product

- 1<sup>st</sup> step: Gathering component data by CIR
- 2<sup>nd</sup> step: Analysis and calculation
- 3<sup>rd</sup> step: Risk assessment plan

# Risk analysis

## 1<sup>st</sup> step

- Gathering all the data concerning the component: A CIR is sent to the supplier



- Check obsolescence or shrink status of the component,
- Technological node used,
- Wafer plant names and locations,
- Assembly plants/subcontractors names and locations
- All test results (wafer, die and package levels)

# Risk analysis

2<sup>nd</sup> step

- Analysis of the CIR form



# Risk analysis

## Reliability tests results at wafer level



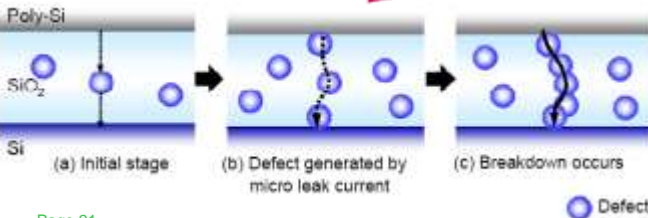
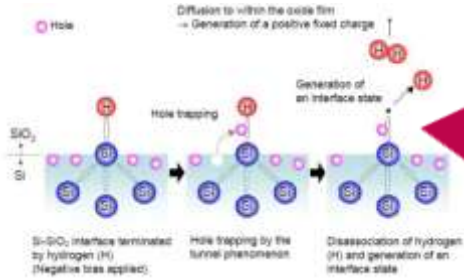
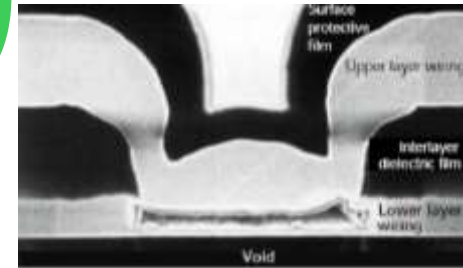
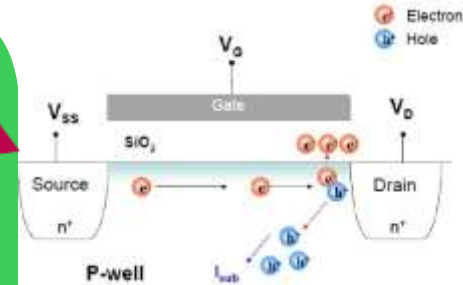
!!! WEAR OUT !!!

Hot Carrier Injection (HCI)

Time Dependent Dielectric Breakdown (TDDB)

Electromigration (EM)

Negative Bias Thermal Instability (NBTI)



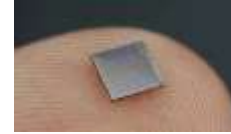
Source: Semiconductor Device Reliability Verification (SONY)

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Schneider Electric

# Risk analysis

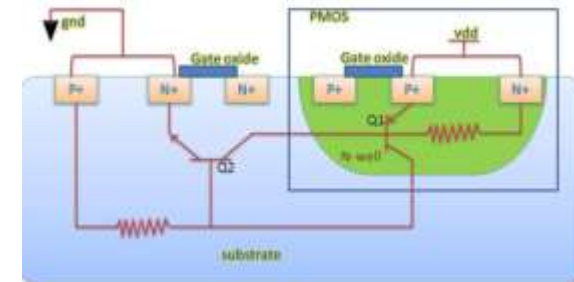
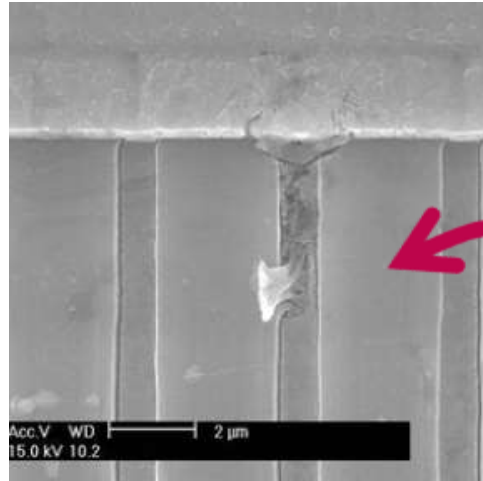
## Reliability tests results at device level



High Temperature Operating Life (HTOL)

Latch Up (LU) at max. operating temperature

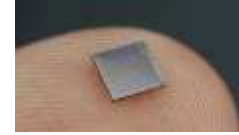
Electro-Static Discharge (ESD)



Source: <http://vlsiuniverse.blogspot.fr/2013/03/latchup-condition-in-cmos-devices.html>  
Failure Signature of electrical overstress on power MOSFETs

# Risk analysis

Reliability tests results at die level (applying to non volatile memories and IC's with flash or non volatile memories embedded )



**Non-volatile Memory Uncycled High Temperature Data Retention (UCHTDR)**

**Non-volatile Memory Cycling Endurance (NVCE)**

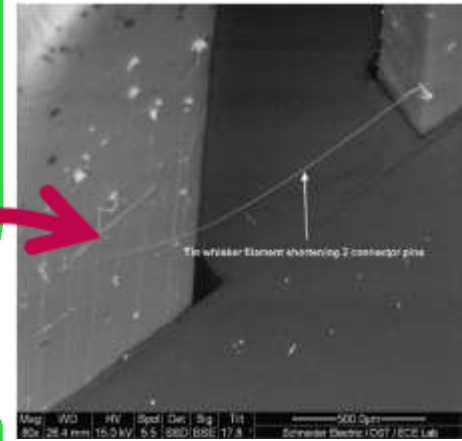
**Non-volatile Memory Post Cycling High Temperature Data Retention (PCHTDR)**

# Risk analysis

## Reliability tests results at package level

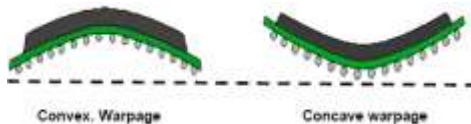


High Temperature Storage (HTS)  
Temperature Humidity Bias (THB) or Highly Accelerated Stress test (HAST)  
Thermal Cycling (TC)  
Bond Pull Strength (BPS)  
Bond Shear (BS)  
Solderability (SD)  
Tin whisker's tests excepted to BGA package



## Qualification tests applying only to BGA packages:

Solder Ball Shear (SBS)  
Thermal warpage characterization test

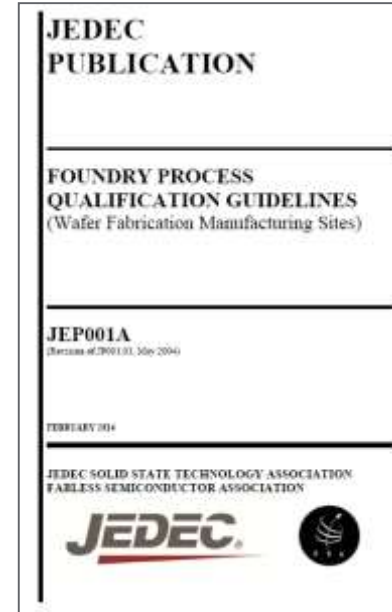
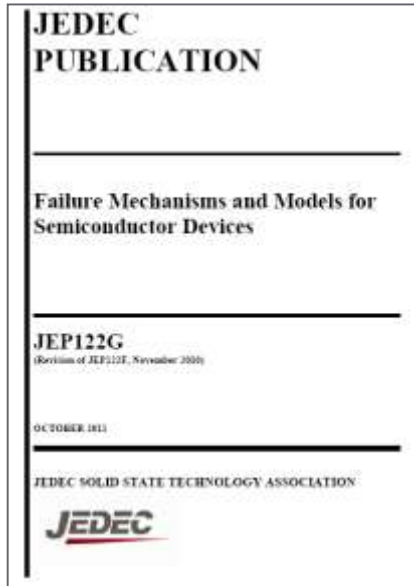


Source: <http://www.tpt-wirebonder.com/en/accessories/add-ons/h53-pull-tester.html>  
JESD22 B112

# Risk analysis

## 2<sup>nd</sup> step

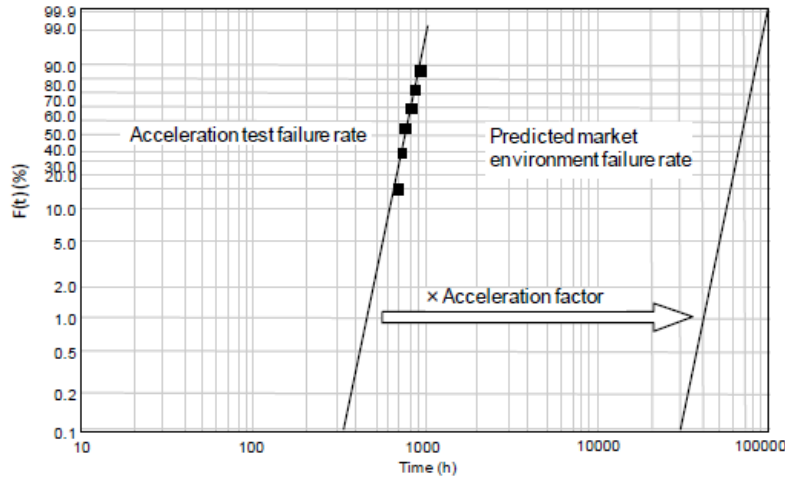
- Check if all the tests have been performed in accordance with JEDEC Standards (or AEC-Q100): JESD47I / JEP122G / JEP001A



# Risk analysis

## 2<sup>nd</sup> step

- Use acceleration factors and JEDEC models in order to validate the coverage of the mission profile by the reliability tests performed by the supplier



### Arrhenius

$$AF = e^{\frac{E_a}{k} \left( \frac{1}{T_{use}} - \frac{1}{T_{Test}} \right)}$$

### Black Model

$$AF = \left( \frac{J_{use}}{J_{test}} \right)^{-n} * e^{\frac{E_a}{k} \left( \frac{1}{T_{use}} - \frac{1}{T_{Test}} \right)}$$

### Hallberg-Peck Model

$$AF = \left( \frac{RH_{Test}}{RH_{use}} \right)^m$$



# Risk analysis

## 3<sup>rd</sup> step

- Identify the risks
- Propose a risk assessment plan

Risk n°	Description of risk (describe risks of use in Schneider products that are not covered by Manufacturer's qualification)	Risk Assessment Proposal (describe proposed assessment works necessary for the use of the component in targeted Schneider products)
1	<b>Risk of poor quality of assembly of BGA package on electronic boards for ASET assembly site:</b> The supplier did not provide the SBS, SD and warpage tests	Ask the supplier to provide SBS, SD and warpage test results.
2	<b>Risk of poor quality of assembly of BGA package on electronic boards for CML assembly site:</b> BGA thermal warpage characterization test results are missing.	Ask the supplier to provide BGA thermal warpage characterization results.

# Risk analysis

## Gap coverage following risk analysis

- Reliability tests missing: ask the supplier to provide the missing test  
→ Example: missing HTS test
- Reliability tests not covering the mission profile: ask the supplier to perform the test with the conditions to cover the mission profile or perform the test in our laboratory  
→ Example: data retention test
- Technological analyses (verification of the process quality, wafer fab unknown, new technology...)

A woman with blonde hair, wearing a dark jacket and a red and blue patterned scarf, is smiling and looking down at a white smartphone in her hands. She is wearing large hoop earrings. The background is a blurred city street with other people and buildings.

## Difficulties / Concerns

# Difficulties / Concerns

- Difficulties in getting the relevant data from supplier (especially for wear out test results) as companies buy only small quantities of components.
- Difficulties in getting the activation energy value for certain test (data retention, HCI...)
  - “Secret” values for component companies (can reveal the maturity of the process...)
- Models used are getting obsolete (combination of failures mechanisms....) and in some points the JEDEC has reached its limit.
- Use multisource to avoid obsolescence: merging of several companies reduce the choice of component supplier (NXP/Freescale, Cypress/Spansion....)

A smiling man with glasses on his head, wearing a pink shirt, is sitting at a desk in an office. He is looking towards the left. A laptop is in the foreground, and a blue filing cabinet is on the right. The background is a blurred office environment.

THANK YOU.

# Questions?



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